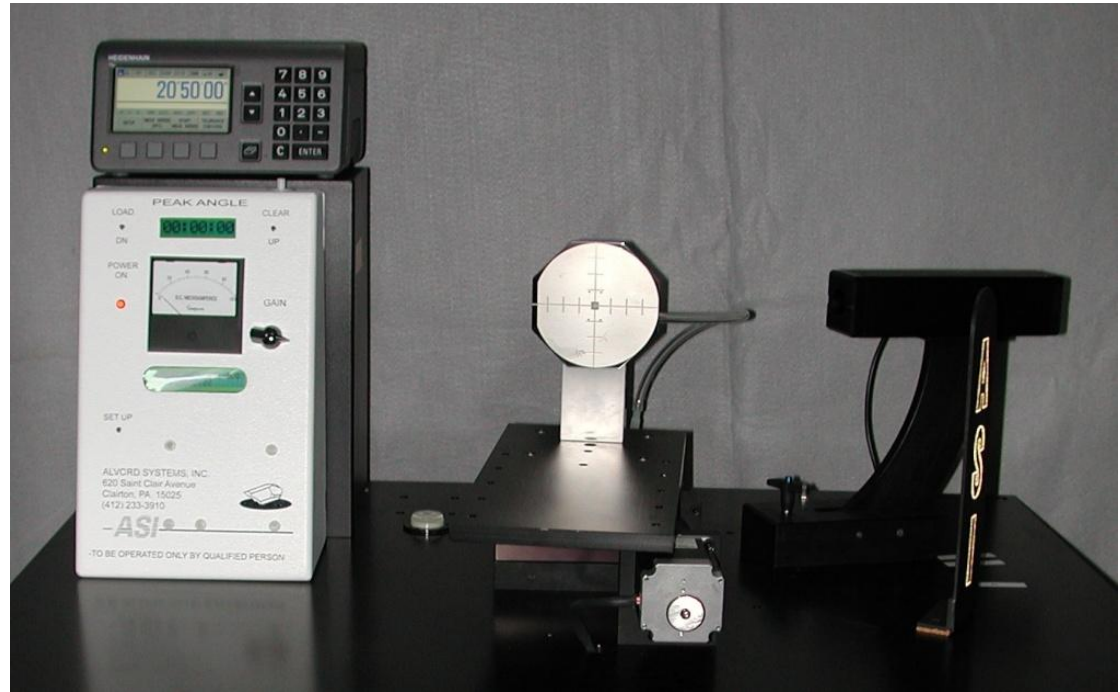




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Model 45

Crystal Diffraction Goniometer X-RAY SYSTEM



Simplistic operations

Low Energy X-ray

Custom Fixtures

Precision measurements +/- 5 Arc Sec

Automated Peak detection or Manual

Applications (Production Floor measurements/ QA inspections)

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ASI

Model 45 Automation

A crystal sample is mounted on the goniometer and rotated about an axis while being irradiated or illuminated by a monochromatic X-ray beam generated by an additional crystal called the reference or collimating crystal used to provide a highly directional beam, with a high level of resolution, accuracy and repeatability achieved.

Computer control provides full control over angular position and rotation of the goniometer as well as real-time feedback from the detection circuitry. By utilizing the computer and specialized software, multiple and simultaneously measurements of the goniometer position and detector output can be obtained. Serial data output via USB. Employing this type of computer diffraction system allows for resolution accuracy of ± 5 arc seconds.



The Model M45 is a single operator precision X-ray diffraction system for cores, slabs, and ingots, designed to provide years of accurate and reliable service in today's high-tech production environment.

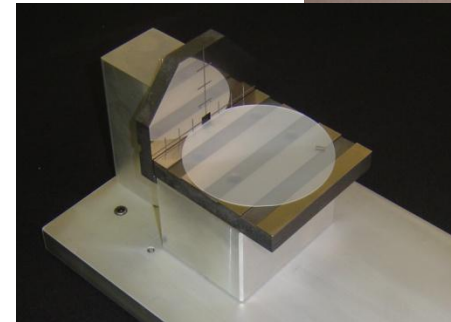
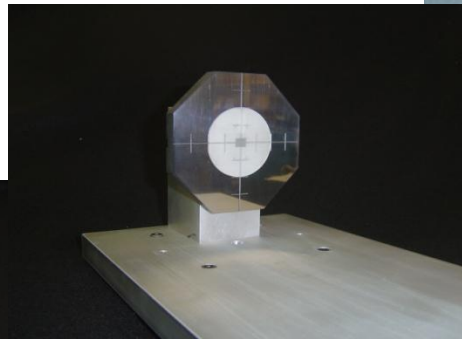
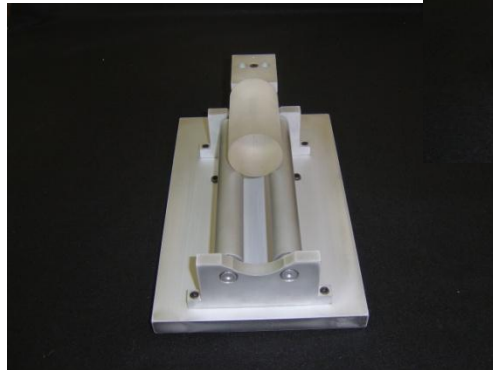
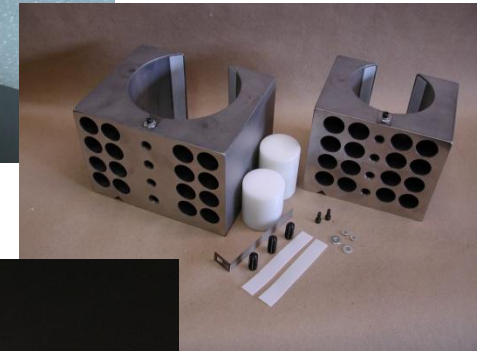
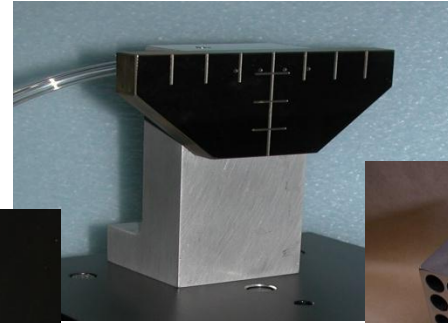
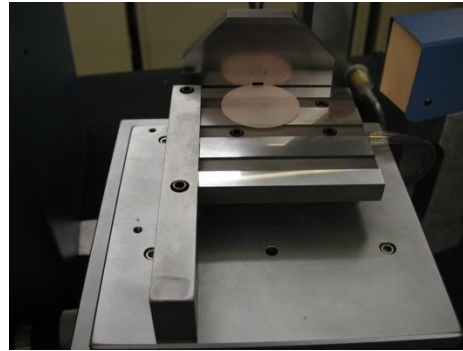
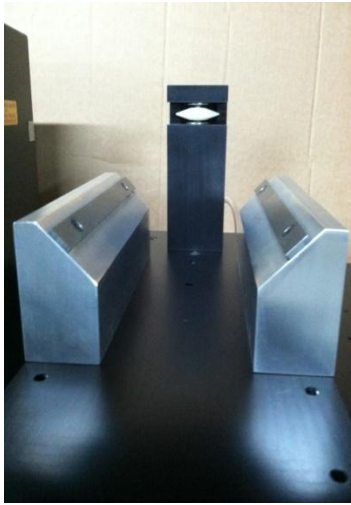
Custom Enclosures



Manual scan with Analog display provides basic diffraction capabilities for lower production applications while maintaining the high level of resolution, accuracy and repeatability



Alvord Systems M45 System Provides the Technology for Integrating Crystal Diffraction Measurements into Your Production Process



Flexibility for X-Ray Diffraction Measurements on Production and Final Crystal Products

Custom Design & Assembling of X-ray Diffraction Systems

ALVORD SYSTEMS, INC.

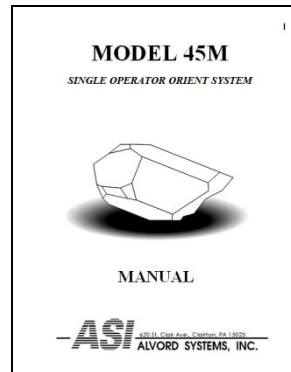
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- **Custom Design**

- Automated Scanning and Peak Detection
- Operational Flexibility Production / QA Applications
- Precision Diffraction Measurements +/- 5 Arc Sec

Alvord Systems Provides the Technology and Flexibility for Crystal X-Ray Orientation within your Production Process